

雑誌発表

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3. Absolute thickness measurement using automatic fractional fringe order method: Minghong Tsai, Hongxin Huang, Masahide Itoh, Toyohiko Yatagai, *Proceedings of SPIE*, Vol. 3897(1999)
4. Multiple Wavelength Fringe Scanning Profilometry for Wide Gapped Sample: Minghong Tsai, Hongxin Huang, Masahide Itoh and Toyohiko Yatagai, Accepted to be published in *Optical Engineering* (1999).
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Generalization theory of wide-band light interferometry
蔡 明宏、原田建治、黄 洪欣、田 栄隆、伊藤雅英、谷田貝豊彦、光学
(投稿中)